

(12) UK Patent Application (19) GB (11) 2 257 295 (13) A

(43) Date of A publication 06.01.1993

(21) Application No 9113557.4

(22) Date of filing 21.06.1991

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(51) INT CL⁵
H01J 37/20, G01N 1/28

(52) UK CL (Edition L)
H1D DHD D14C
G1B BCX
U1S S2135 S2170

(56) Documents cited
GB 1405567 A EP 0371572 A2 EP 0326349 A2
US 4705705 A

(58) Field of search
UK CL (Edition K) G1B BCX, H1D DAH1 DHD DHE
DHX DMH
INT CL⁵ G01N, G02B, H01J

(54) Sample holder for use in a mass spectrometer

(57) A sample holder, e.g. for laser desorption mass spectrometry, comprises a plate 1 having a flat, which flat includes a first region 5 having a smooth surface surrounding a second region 7 having a rough surface. The second region 7 defines the location for loading a sample. A stainless steel plate has a first region 5 with a polished surface of roughness less than 0.025 microns and a central circular second region 7 more wettable than the first with a roughness of 0.4 microns formed by dry blasting.

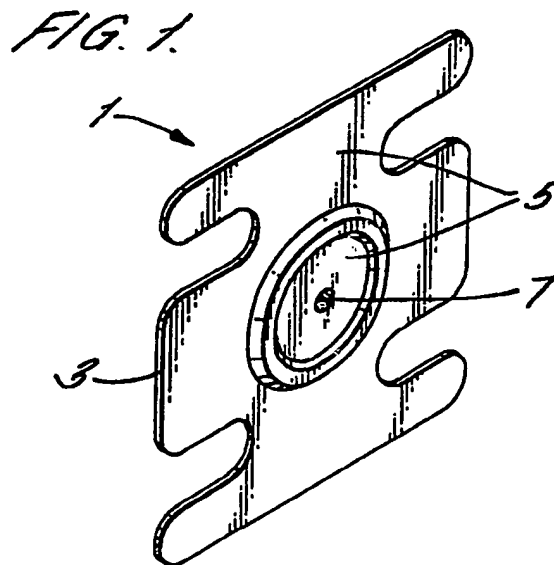


FIG. 1.

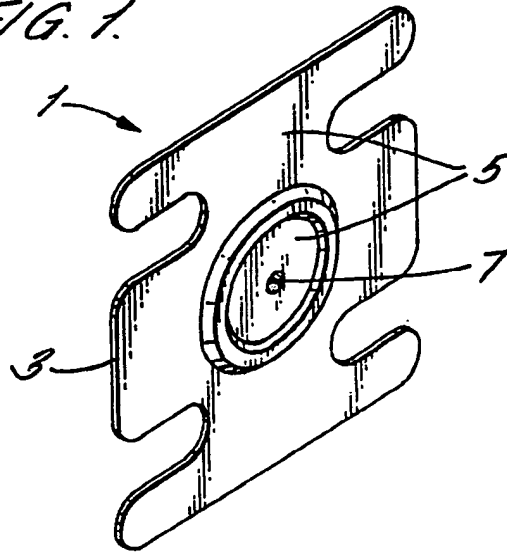


FIG. 2.

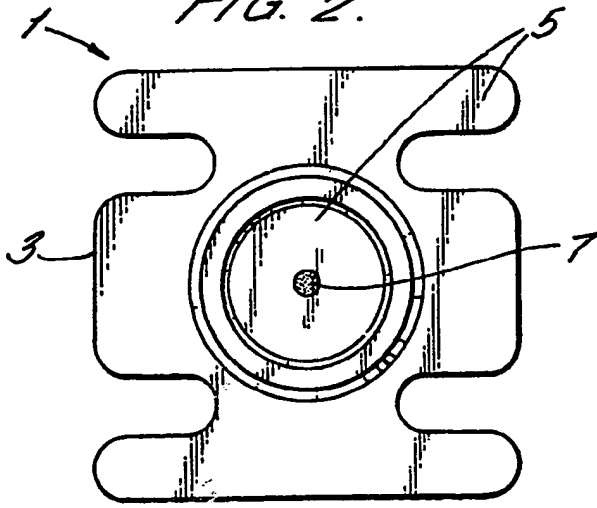
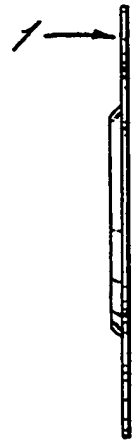


FIG. 3.



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SAMPLE HOLDER FOR USE IN A MASS SPECTROMETER

This invention relates to a sample holder to be used in the analysis of a sample by Laser Desorption mass spectrometry (LDMS). In LDMS, ions are sputtered from the surface of a condensed phase sample by photon bombardment and subjected to mass analysis.

There are many embodiments of Laser Desorption mass spectrometers which differ in detail. An important feature of certain embodiments is the use of a matrix material in which the analyte of interest is dispersed. In the procedure described by M. Karas et. al. (Int. J. Mass Spectrom. Ion Processes 78 53 (1987)), a large molar excess of a matrix which has a strong absorption at the wavelength of the incident radiation is mixed with the sample to be analysed. For example, they dissolved a sample of a bovine insulin in an aqueous solution containing a thousand-fold molar excess of Nicotinic Acid (59-67-6). A drop of the solution was placed on a metal plate, evaporated to dryness, introduced into the mass spectrometer, and irradiated with 266nm ultraviolet photons from a frequency quadrupled pulsed Neodymium YAG laser. Desorbed ions were accelerated to an energy of 3 keV and analysed by measuring their time of flight to an electron multiplier detector.

The sensitivity of analysis by a Laser Desorption mass spectrometer depends critically on the detailed sample loading procedure. Ions can only be produced from those regions of the sample deposit which are irradiated by the laser beam. Sample which is not irradiated is wasted. The laser beam is generally focused to a small spot, typically 0.1mm diameter. In principle, such a

laser beam can be rastered over a much larger area. However, it is difficult to design extraction optics to accept ions from a very large area and focus them onto the detector without introducing a time spread which would degrade the mass resolution of the instrument. In addition, the mechanism to achieve controllable rastering over a large area adds cost and complexity to the instrument. A more desirable approach is to restrict the size of the sample deposit to a practical minimum. This raises the difficulty of identifying the precise spot at which the sample should be loaded on a relatively large area sample holder. It is also necessary to constrain the droplet to this spot while it dries. An object of the present invention is to provide a means of constraining the droplet to a predefined area while the solvent evaporates.

Identifying the spot at which the sample is to be loaded is not a trivial matter. The printing of marks using commercially available inks would limit the range of solvent systems which could be used for loading samples. Indented or engraved lines tend to attract the sample away from the desired spot by capillary attraction. For mass analysis by Time-of-Flight, it is important that the area from which ions originate is essentially flat, otherwise the variation in path length will cause a reduction in mass resolution. For this reason, a dished indentation to locate and contain the sample droplet is not feasible. Another object of the present invention is to provide a sample holder in which the optimum location for the sample deposit is clearly identified.

A further critical aspect of the sample loading procedure concerns the uniform drying of the droplet of sample and matrix solution. For reproducible results, it is necessary to achieve a reasonably homogeneous crystalline deposit on the sample target. If, for example, the sample and matrix have a tendency to separate on crystallisation, a slowly drying droplet may deposit the majority of the sample as a peripheral ring which is outside the area to be irradiated. Thus, a further object of the present invention is to provide a sample holder which enables a reasonably homogeneous sample deposit to be achieved.

The present invention provides a sample holder for use in mass spectrometry comprising a plate having a flat, said flat including a first region having a smooth surface surrounding a second region having a rough surface, said second region defining the location for loading a sample.

A smooth surface refers to a surface that is generally lustrous and scratch free. A rough surface refers to a surface that is rough on a generally microscopic scale.

In contrast to the smooth region, the rough region provides an area of good wettability so that a droplet is constrained to this region. The visual contrast between the smooth and rough regions also enables the location for the sample deposit to be clearly identified. Furthermore, the rough region provides a multitude of nucleation sites scattered around the area to be irradiated, encouraging rapid crystallisation of the sample so that a reasonably homogeneous crystalline deposit is achieved.

In general, the surface of the second region should be sufficiently rough relative to the surface of the first region such that the second region is more wettable than the first. For example, sufficient contrast is achieved if the first region has an average roughness of less than about 1 microinch or 0.025 micron and the second region has an average roughness of greater than about 8 microinch or 0.2 micron.

The first region is preferably polished to a high quality finish so that wetting in this region is extremely difficult. This serves to encourage the sample away from this region and onto the rough region to assist in loading. Furthermore, the boundary between the smooth and rough regions will be more sharply defined.

In a preferred embodiment the second region, having a rough surface, is located at the centre of the sample holder and has the form of a circular spot.

An example of an embodiment of the present invention will now be described with reference to the drawings, in which:-

Figure 1 is a perspective view of a preferred embodiment of the present invention;

Figure 2 is a plan view of the embodiment shown in Figure 1, and

Figure 3 is a side view of the embodiment shown in Figures 1 and 2.

The sample holder comprises a plate 1, preferably made from stainless steel, although other suitable materials may be used, and is large enough to be handled

without the use of special tools. The periphery 3 of the holder 1 is shaped so as to facilitate location of the target within the mass spectrometer. A first region 5 of the sample holder surrounds a second region 7 being a circular area of diameter 2mm in the centre of the front face.

The surface of region 5 has an average roughness of less than 1 microinch or 0.025 micron which can be produced, for example, by polishing and buffing with progressively fine abrasives or by electrolytic methods. The surface of the central spot 7 has an average roughness of the order of 16 microinch or 0.4 micron and is generally roughened by abrasion. The preferred method of abrasion is dry blasting with 180/220 mesh aluminium oxide expelled from a nozzle by compressed air at a rate of 14 cubic feet per minute and applied through an appropriate stencil. There are clearly many other methods of creating a well defined region of appropriate roughness and this invention is not intended to be restricted to any particular abrasion process.

The contrast between the roughened spot 7 and the surrounding polished surface 5 is sufficient to give a clear visual indication of where to load the sample. The roughened surface also tends to retain the droplet through being more wettable than the polished surface. Finally, the microscopically roughened surface provides a multitude of nucleation sites which ensure uniform crystallisation.

CLAIMS

1. A sample holder for use in mass spectrometry, comprising a plate having a flat, said flat including a first region having a smooth surface surrounding a second region having a rough surface, said second region defining the location for loading a sample.
2. A sample holder for use in mass spectrometry, including a plate having a flat, said flat including a first region surrounding a second region, wherein the second region is more wettable than the first region by virtue of surface roughness and defines the location for loading a sample.
3. A sample holder as claimed in any preceding claim, wherein said first region has a surface roughness of less than about 0.025 micron.
4. A sample holder as claimed in any preceding claim, wherein the second region has an average roughness of the order of 0.4 micron.
5. A sample holder as claimed in any preceding claim, wherein said second region is roughened by dry blasting.
6. A sample holder as claimed in any preceding claim, wherein said second region is positioned at the centre of the sample holder.
7. A sample holder as claimed in any preceding claim, wherein said second region is a circular spot.

8. A method of loading a sample for Laser Desorption mass spectrometer analysis onto a sample holder including the step of roughening the surface of a discrete region of the holder said region defining the location for loading the sample.

9. A sample holder substantially as hereinbefore described with reference to and illustrated by any one of the drawings.

10. A method of loading a sample for Laser Desorption mass spectrometer analysis substantially as hereinbefore described with reference to and illustrated by any one of the drawings.

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Patents Act 1977
Examiner's report to the Comptroller under
Section 17 (The Search Report)

Application number

9113557.4

Relevant Technical fields

(i) UK Cl (Edition K) HID - DHD, DHE, DHX, DMH,
 DAHI, GIB - BCX

(ii) Int Cl (Edition 5) HOIJ; G0IN; G02B

Search Examiner

R H LITTLEMORE

Databases (see over)

(i) UK Patent Office

(ii)

Date of Search

22 OCTOBER 1991

Documents considered relevant following a search in respect of claims 1-10

Category (see over)	Identity of document and relevant passages	Relevant to claim(s)
X	GB 1405567 (Boden Perkin-Elmer) - eg. see Figure 2 and page 1 line 58 - page 2 line 60	1,2,8 at least
X	EP 0371572 A2 (ICR Research) - eg. see Figures 12, 13, 14 and column 11 line 41 - column 12 line 10	1,2,8 at least
X	EP 0326349 A2 (Hycor Biomedical) - eg. see Claims 6, 13 and 15	1,2,8 at least
X	US 4705705 (Bross) - eg. see column 3 lines 29-59	1,2,8 at least

Category	Identity of document and relevant passages	Relevant to claim(s)

Categories of documents

X: Document indicating lack of novelty or of inventive step.

Y: Document indicating lack of inventive step if combined with one or more other documents of the same category.

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P: Document published on or after the declared priority date but before the filing date of the present application.

E: Patent document published on or after, but with priority date earlier than, the filing date of the present application.

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